

# CHARACTERISATION OF THIN LAYERS ANTI-REFLECTIVE COATING

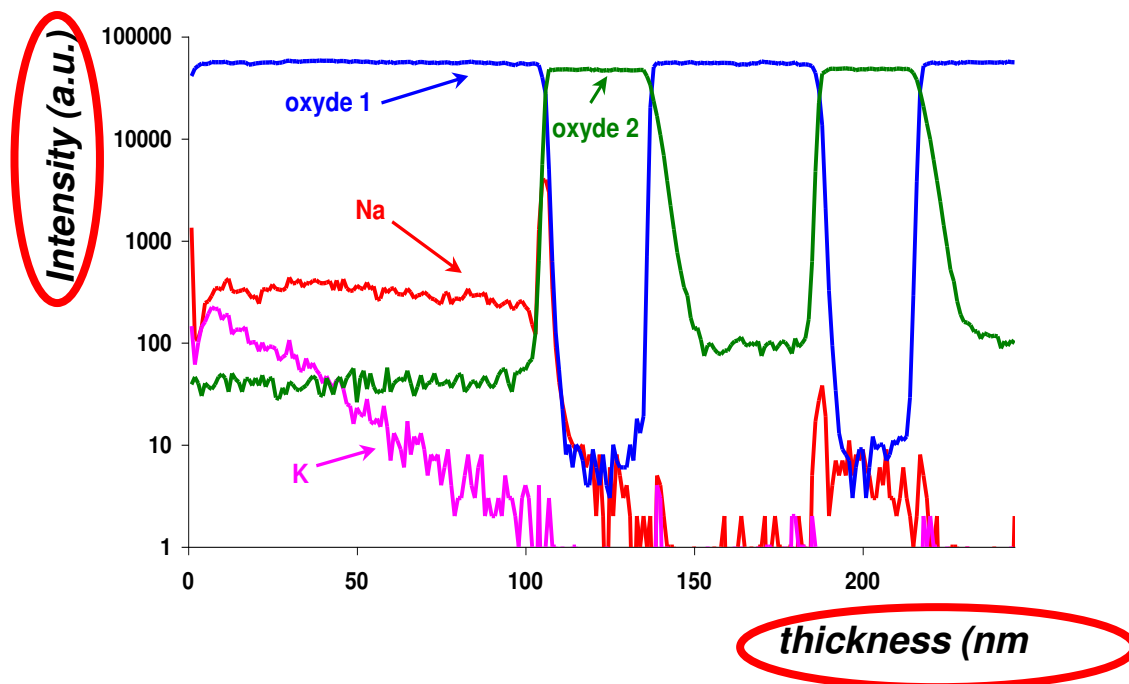


**Subject:** In a thin oxide multilayers material (50-100 nm), how to check the presence and determine the nature of contaminants in the layers and at the interfaces?

## Techniques used : SIMS

- ✓ High resolution depth profiling
- ✓ Very high sensitivity

## Results :



## Conclusion :

- ✓ Sodium traces in the 1st layer and at the 1st interface
- ✓ Potassium diffusion in the 1st layer
- ✓ Diffusion of oxide 2 into oxide 1
- ✓ Traces of oxide 2 in oxide 1